Search	Notes
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Application/Control No.	

Applicant(s)/Patent under Reexamination
LEE ET AL.

10/824,283

Examiner

Art Unit

Nathan Wiehe

3745

SEARCHED				
Class	Subclass	Date	Examiner	
416	97R,96R, 96A	8/18/2005	NEW NEW	
415	115,116	8/18/2005	NEW	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
416/97R,96R,96A 415/115,116 Christopher Verdier	8/18/2005	NEU
Text search (See EAST search history)	8/18/2005	NEW
Inventor Name Search	8/18/2005	NEW
PLUS search	8/18/2005	NEW